

Aleksander Labuda

List of Publications by Year in descending order

Source: <https://exaly.com/author-pdf/11186151/publications.pdf>

Version: 2024-02-01

19
papers

780
citations

687335

13
h-index

839512

18
g-index

19
all docs

19
docs citations

19
times ranked

1253
citing authors

#	ARTICLE	IF	CITATIONS
1	Tapping Mode AFM Imaging in Liquids with blueDrive Photothermal Excitation. <i>Microscopy Today</i> , 2018, 26, 12-17.	0.3	13
2	Static and dynamic calibration of torsional spring constants of cantilevers. <i>Review of Scientific Instruments</i> , 2018, 89, 093701.	1.3	4
3	Fast, High Resolution, and Wide Modulus Range Nanomechanical Mapping with Bimodal Tapping Mode. <i>ACS Nano</i> , 2017, 11, 10097-10105.	14.6	110
4	Generalized Hertz model for bimodal nanomechanical mapping. <i>Beilstein Journal of Nanotechnology</i> , 2016, 7, 970-982.	2.8	65
5	Calibration of higher eigenmodes of cantilevers. <i>Review of Scientific Instruments</i> , 2016, 87, 073705.	1.3	40
6	Daniell method for power spectral density estimation in atomic force microscopy. <i>Review of Scientific Instruments</i> , 2016, 87, 033704.	1.3	5
7	Quantitative measurements of electromechanical response with a combined optical beam and interferometric atomic force microscope. <i>Applied Physics Letters</i> , 2015, 106, .	3.3	96
8	Contact resonance atomic force microscopy imaging in air and water using photothermal excitation. <i>Review of Scientific Instruments</i> , 2015, 86, 083706.	1.3	29
9	Bias-Dependent Molecular-Level Structure of Electrical Double Layer in Ionic Liquid on Graphite. <i>Nano Letters</i> , 2013, 13, 5954-5960.	9.1	142
10	Stochastic simulation of tip-sample interactions in atomic force microscopy. <i>Applied Physics Letters</i> , 2012, 101, 113105.	3.3	7
11	Retrofitting an atomic force microscope with photothermal excitation for a clean cantilever response in low Q environments. <i>Review of Scientific Instruments</i> , 2012, 83, 053703.	1.3	39
12	Atomic Force Microscopy in Viscous Ionic Liquids. <i>Langmuir</i> , 2012, 28, 5319-5322.	3.5	45
13	The noise of coated cantilevers. <i>Nanotechnology</i> , 2012, 23, 025503.	2.6	27
14	Stochastic noise in atomic force microscopy. <i>Physical Review E</i> , 2012, 86, 031104.	2.1	18
15	Exploiting cantilever curvature for noise reduction in atomic force microscopy. <i>Review of Scientific Instruments</i> , 2011, 82, 013704.	1.3	12
16	Switching Atomic Friction by Electrochemical Oxidation. <i>Langmuir</i> , 2011, 27, 2561-2566.	3.5	45
17	Decoupling conservative and dissipative forces in frequency modulation atomic force microscopy. <i>Physical Review B</i> , 2011, 84, .	3.2	46
18	High-resolution friction force microscopy under electrochemical control. <i>Review of Scientific Instruments</i> , 2010, 81, 083701.	1.3	36

#	ARTICLE	IF	CITATIONS
19	Robust and Efficient Parametric Spectral Density Estimation for High-Throughput Data. Technometrics, 0, , 1-22.	1.9	1